

Resource Summary Report

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Surface Modified Amperometry CMOS IC

RRID:SCR_017082

Type: Tool

Proper Citation

Surface Modified Amperometry CMOS IC (RRID:SCR_017082)

Resource Information

URL: <https://link.springer.com/article/10.1007%2Fs00424-017-2067-y>

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Description: Integrated circuit device used as tool for amperometry measurement as replacement of conventional carbon fiber microelectrode. Surface modified structures with SU 8 microwells increases life span of each individual device and achieves single cell measurement efficiency by trapping cells inside microwells.

Synonyms: Surface Modified Amperometry Complementary Metal Oxide Semiconductor IC

Resource Type: instrument resource

Defining Citation: [PMID:28889250](#)

Keywords: instrument, device, CMOS, amperometry, measurement, chip, microelectrode, microwell, cell, semiconductor

Resource Name: Surface Modified Amperometry CMOS IC

Resource ID: SCR_017082

Record Creation Time: 20220129T080333+0000

Record Last Update: 20260903T235416+0000

Ratings and Alerts

No rating or validation information has been found for Surface Modified Amperometry CMOS IC.

No alerts have been found for Surface Modified Amperometry CMOS IC.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We found 1 mentions in open access literature.

Listed below are recent publications. The full list is available at [dkNET](#) .

Huang M, et al. (2019) Drug testing complementary metal-oxide-semiconductor chip reveals drug modulation of transmitter release for potential therapeutic applications. Journal of neurochemistry, 151(1), 38.